

presented by



UEFI and Security Development Lifecycle (SDL) – Unit Testing

Fall 2018 UEFI Plugfest

October 15 – 19, 2018

Presented by Trevor Western (Insyde Software)

Agenda



- SDL and Unit Testing
- Why Unit Test
- Real world example
- Recommendations
- Resources

The Security Development Lifecycle



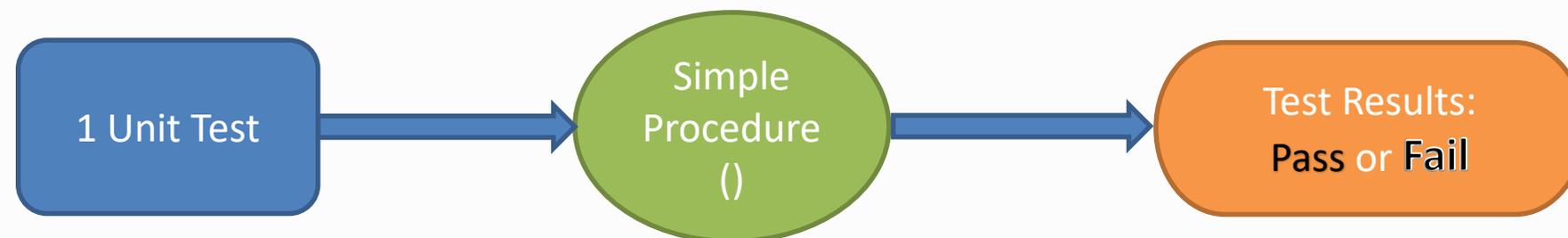
- The SDL improves the capability to support, design, develop, test and release secure software.
 - Improved [support](#) through training and in-house security expertise.
 - Improved [design](#) using risk assessment and threat modeling.
 - Improved [development](#) with best practices that minimize chances of attacks.
 - Improved [testing](#) using tools to detect and test for vulnerabilities.
 - Improved [response](#) by root causing, deploying fixes, informing customers and updating tests.
- The Security Development Lifecycle promotes continuous improvement.





SDL and UEFI Unit Testing

- What are Unit Tests?
 - Collections of test cases that verify the functionality and behavior of new code; and prevent “breaking” previously checked in code.
 - The scope of a test case is limited to the smallest piece of testable code
 - Meant to run automatically and frequently.
 - Can be used to guide software development (Test-Driven Development or Test-First-Code-After Development).



SDL and UEFI Unit Testing



- Why do we need Unit Tests?
 - Provide visible evidence that the new code functions and behaves correctly in the form of PASSED/FAILED report.
 - Prevent new code from “breaking” previously checked in code.
 - Provide reproducible and verifiable results for QA reports.
 - Promote good software development practices (SDL)

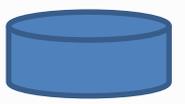


SDL and UEFI Unit Testing

- Many tests exist for the UEFI Runtime interfaces, such as the UEFI Self-Certification Test (SCT), and the Canonical Firmware Test Suite (FWTS)
- Start with tests for internal UEFI modules for pre-OS
- You can't write Unit Tests for everything at once
 - Start with writing Unit Tests for bugs; or
 - Write Unit Tests for new code
- Keep the Unit Test code in same location as UEFI module code
 - They should be maintained together
 - Use a Unit Test Framework (Test Harness) to manage the tests

SDL and UEFI Unit Testing



- A Unit Test Harness provides the following capabilities:
 - A common language to express test cases (usually 'C') 
 - A common language to express the expected results True or False
 - Access to the features of the production code 
 - A place to collect the Unit Test cases for the project 
 - A mechanism to run all the Unit Test cases 
 - A small summary report of the test suite success or failure Pass x : Fail y 
 - A detailed report of any test failures 
- The following slides show an example of Unit Testing for a bug



SDL and UEFI Unit Testing

- The 'MacEmpty' code below checks if a Mac Address is not null. It has a bug.

```
MacEmpty( IN UINT8 *MacAddr ){
    UINTN Index;
    UINT8 TempValue = 0;
    For (Index=0; Index < 4; Index++) {
        TempValue = TempValue + UINT8(MacAddr[Index]);
    }
    If( TempValue == 0) return (TRUE)
    Else return (FALSE);
};
```

- Bug: TempValue overflows (sum of MacAddr[0,1,2,3] is a 32 bit value); but only causes a problem if TempValue % 0x100 = 0 (e.g., 0x200; 0x300; etc). This is a really strange bug.

SDL and UEFI Unit Testing



- Create a Unit Test for the MacEmpty() routine. Feed MacEmpty() test data to show the normal working case.

```
UNIT_TEST_BEGIN (UT_IsMacZero?)
{
    UINT8 TestMacAddrs[4] = {0x00, 0x00, 0x00, 0x00};

    if (MacEmpty(TestMacAddrs) != TRUE) {
        UNIT_TEST_RESULT("MacEmpty Failed Empty Mac test", FAILED)
    } else
        UNIT_TEST_RESULT("", PASS)
};
UNIT_TEST_END
```

- A simple test proves you did not break the working code



SDL and UEFI Unit Testing

- Now create a Unit Test to see if you can catch the bug

```
UNIT_TEST_BEGIN (UT_Is8BitOverflowBugFixed?)
{
    UINT8 TestMacAddrs[4] = {0x00, 0xFF, 0x01, 0x00};

    if (MacEmpty (TestMacAddrs) == TRUE) {
        UNIT_TEST_RESULT ("MacEmpty has 8BitOverflow bug", FAILED)
    } else
        UNIT_TEST_RESULT ("", PASS)
};
UNIT_TEST_END
```

- A simple test proves the bug is fixed
 - But Unit Test on the unfixed code first



SDL and UEFI Unit Testing

- Collect the Unit Test together for the Test Harness:

```
UNIT_TEST_GROUP_BEGIN ("MacEmpty")  
    & UT_IsMacZero? ()  
    & UT_Is8BitOverflowBugFixed? ()  
UNIT_TEST_GROUP_END
```

```
<make all  
Compiling "MacEmpty" ...  
Running "MacEmpty" ...  
OK (2 tests run, 0 failed)
```

- Setup the Test Harness to run these tests automatically when this code module changes

SDL and UEFI Unit Testing

Recommendations



- Test the Unit Test Code:
 - Make sure you test the Unit Test code with inputs designed to expose the bug in the unfixed code
- New product code has to be testable:
 - Modular design with well-defined API.
 - Separate functional code from UEFI framework details.
- Unit Tests are stored same place as code and managed by Test Harness
 - Update Unit Tests when code is expected to change.
 - Keep in a common code package (e.g. OurUnitTestPkg)

SDL and UEFI Unit Testing

Recommendations

- Don't create a test framework or test harness from nothing
 - Several are available for free and easily adaptable
 - Some are designed to work in a UEFI environment
 - “Implementing MicroPython as a UEFI Test Framework” - Spring 2018 UEFI Plugfest March 26-30, 2018 Presented by Chris McFarland (Intel)



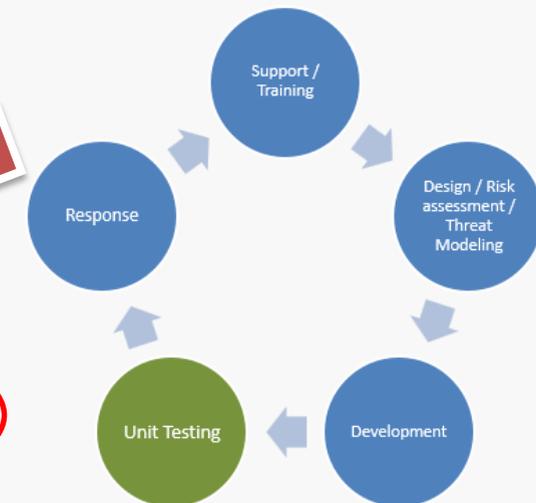
SDL and UEFI Unit Testing



- SDL can now move to the **Response** step:
- Update the Unit Tests to catch the issue

The Security Development Lifecycle

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Resources:



- UEFI test tools - <http://www.uefi.org/testtools>
- “Implementing MicroPython as a UEFI Test Framework” - Spring 2018 UEFI Plugfest March 26-30, 2018 Presented by Chris McFarland (Intel)
- “Practical Unit Testing for Embedded Systems”
<http://www.public.asu.edu/~atrow/ser456/articles/PracticalUnitTesting.pdf>
- “Test-Driven Development for Embedded C” by James Grenning
<http://www.pragprog.com/titles/jgade>
- Unity test framework / test harness
<http://unity.sourceforge.net>

Thanks for attending the Fall 2018
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For more information on the Unified
EFI Forum and UEFI Specifications,
visit <http://www.uefi.org>

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